# 74ACT11112 DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOP WITH CLEAR AND PRESET

SCAS064A - D3339, JUNE 1989 - REVISED APRIL 1993

<ul> <li>Inputs Are TTL-Voltage Compatible</li> <li>Fully Buffered to Offer Maximum Isolation</li> </ul>	D OR N PACKAGE (TOP VIEW)					
From External Disturbance						
<ul> <li>Flow-Through Architecture Optimizes</li> <li>PCB Layout</li> </ul>	1Q 2 15 1 1K 1Q 3 14 1 1CLK					
<ul> <li>Center-Pin V<sub>CC</sub> and GND Configurations</li> <li>Minimize High-Speed Switching Noise</li> </ul>	GND [] 4 13 ] 1CLR 2Q [] 5 12 ] V <sub>CC</sub>					
EPIC <sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-μm Process	2Q [] 6 11 ] 2CLR 2PRE [] 7 10 ] 2CLK					
● 500-mA Typical Latch-Up Immunity at 125°C	2J [ 8 9] 2K					

**Package Options Include Plastic Small-Outline Packages and Standard** Plastic 300-mil DIPs

#### description

This device contains two independent J-K negative-edge-triggered flip\_flops. A low level at the PRE or CLR input sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the clock pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The 74ACT11112 is characterized for operation from – 40°C to 85°C.

FUNCTION TABLE								
	INPUTS						PUTS	
	PRE	CLR	CLK	J	К	Q	Q	
	L	Н	Х	Х	Х	н	L	
	н	L	Х	Х	Х	L	Н	
	L	L	Х	Х	Х	н†	H‡	
	н	Н	$\downarrow$	L	L	Q <sub>0</sub>	$\overline{Q}_0$	
	Н	Н	$\downarrow$	Н	L	н	L	
	Н	Н	$\downarrow$	L	Н	L	Н	
	Н	Н	$\downarrow$	Н	Н	TOGGLE		
	н	Н	Н	Х	Х	Q <sub>0</sub>	$\overline{Q}_0$	

<sup>†</sup>This configuration is nonstable; that is, it will not persist when either PRE or CLR returns to the inactive (high) level.

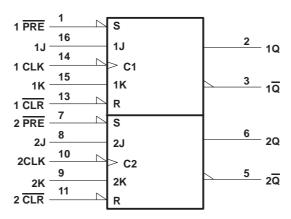
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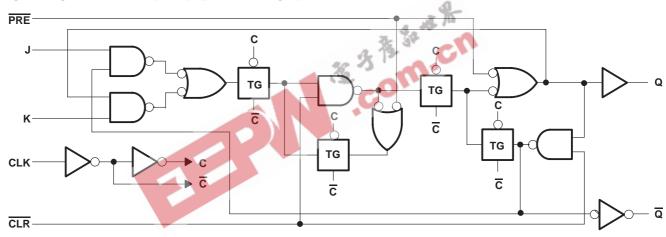
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# logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordnace with ANSI/IEEE Std 91-1984 and IEC Publication 617-42.

### logic diagram, each flip-flop (positive logic)



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, VI (see Note 1)	-0.5  V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	-0.5  V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



#### recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
IOH	High-level output current		-24	mA
IOL	Low-level output current		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
Т <sub>А</sub>	Operating free-air temperature	- 40	85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$T_{A} = 25^{\circ}C$	TEST CONDITIONS $V_{CC}$ $T_A = 25^{\circ}C$	;		MAX	UNIT	
FARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	IVIIIN	IVIAA	UNIT
	I <sub>OH</sub> = – 50 µА	4.5 V	4.4			4.4		
	10H = - 20 mA	<b>5</b> .5 V	5.4			5.4		
VOH	I <sub>OH</sub> = - 24 mA	4.5 V	3.94			3.8		V
		5.5 V	4.94			4.8		
	I <sub>OH</sub> = - 75 mA <sup>†</sup>	5.5 V				3.85		
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1	V
		5.5 V			0.1		0.1	
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.44	
		5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
I	$V_{I} = V_{CC} \text{ or } GND$	5.5 V			± 0.1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			4		40	μA
$\Delta I_{CC}^{\ddagger}$	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			0.9		1	mA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

<sup>‡</sup>This parameter is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 2	25°C	MIN	MAX	UNIT
			MIN	MAX	IVIIIN	MAX	UNIT
fclock	Clock frequency			125		125	MHz
	Pulse duration	PRE or CLR low	4		4		-
tw	Fuse duration	CLK high or low	4		4		ns
	Satur time before CLK	Data high or low	3.5		4.5		
t <sub>su</sub>	Setup time before $CLK\downarrow$	PRE or CLR inactive	2	2 2			ns
th	Hold time after $CLK{\downarrow}$		1.5		1.5		ns



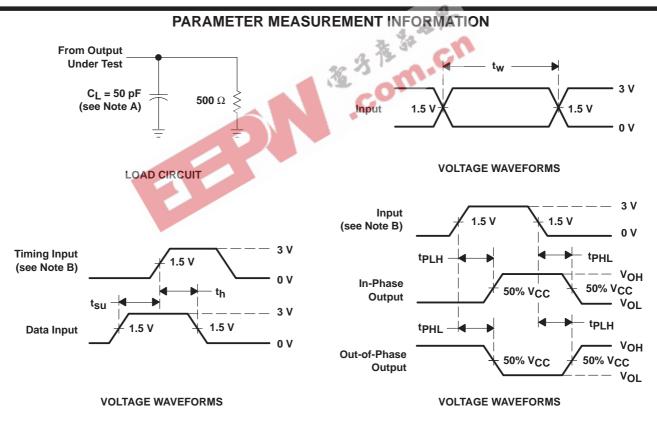
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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	FROM TO $T_A = 25^{\circ}C$		MIN MA	MAX	UNIT	
FARAMETER	(INPUT)		MIN	TYP	MAX	WIIIN	WAA	UNIT
fmax			125			125		MHz
<sup>t</sup> PLH	PRE or CLR	Q or $\overline{Q}$	1.5	3.6	6.3	1.5	6.8	ns
<sup>t</sup> PHL		QUIQ	1.5	4.6	7.4	1.5	8	115
<sup>t</sup> PLH	CLK	Q or $\overline{Q}$	1.5	4.2	7	1.5	7.7	ns
<sup>t</sup> PHL		QUIQ	1.5	4.7	7.4	1.5	8.4	115

# operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

	PARAMETER	TEST CONDITIONS		UNIT
C <sub>pd</sub>	Power dissipation capacitance per flip-flop	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	39	pF



NOTES: A. CL includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub> = 3 ns, t<sub>f</sub> = 3 ns. C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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